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**Semiconductor Process and Yield Analysis Integrated Real-time Management
Method**

Appl. No.	:	10/708,277	Confirmation No. 2276
Applicant	:	Hung-En Tai, Chien-Chung Chen, Sheng-Jen Wang	
Filed	:	February 20, 2004	
TC/A.U.	:	2125	
Examiner	:	GARLAND, STEVEN R	
Docket No.	:	LKSP0045USA0	
Customer No.	:	27765	

Commissioner for Patents
P.O. Box 1450
Alexandria VA 22313-1450

AMENDMENT

5 Sir:

In response to the Office action of February 08, 2006, please amend the above-identified application as follows:

Amendments to the Specification begin on page 2 of this paper.

10 **Amendments to the Claims are reflected in the listing of claims which begins on page 3 of this paper.**

Remarks/Arguments begin on page 7 of this paper.